

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/786,388	STRECK ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

	SEARCHED		
Class	Subclass	Date	Examiner
438	746	8/10/2006	вт
438	747	8/10/2006	вт
438	756	8/10/2006	ВТ

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	8/10/2006	вт		